INTERNATIONAL STANDARD

IEC 60747-14-1

First edition
2000-10

Semiconductor devices –

Part 14-1:
Semiconductor sensors – General and classification

Dispositifs à semiconducteurs –

Partie 14-1:
Capteurs à semiconducteurs –
Généralités et classification

Reference number
IEC 60747-14-1:2000(E)

Publication numbering

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Commission Electrotechnique Internationale
International Electrotechnical Commission
Международная Электротехническая Комиссия

PRICE CODE K

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FOREWORD

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International Standard IEC 60747-14-1 has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47E/157/FDIS	47E/170/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 3.

The committee has decided that the contents of this publication remain unchanged until 2005. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version of this standard may be issued at a later date.